

PME 4352 微機電系統導論 期中考

姓名

學號

一 (20%)	二 (30%)	三 (60%)	總分
19	30	42.5	91.5
		+4.5	96

一、單選題 (20%)

- 無塵室潔淨度等級為 class N, N 越大表示潔淨度越 (A) 低, (B) 高, (C) 相同, (D) 無法辨識
- 和傳統機械相較, 何者為 MEMS 的特色 (A) standard parts, (B) parts assembly, (C) process integration, (D) 以上皆是
- 以下何者不屬於平面加工 (planar fabrication) 技術 (A) IC, (B) MEMS, (C) TFT-LCD, (D) Optical pickup head
- 薄膜沉積的過程如存在孔隙(void)缺陷會造成何種殘餘應力 (A) compression, (B) tension, (C) gradient stress, (D) 以上皆可
- 何種殘餘應力會造成微懸臂結構彎曲 (A) compression, (B) tension, (C) gradient stress, (D) 以上皆可
- 如欲鍍合金薄膜如 AlCu 那一種技術佳 (A) Sputtering, (B) Evaporation, (C) Thermal Growth, (D) Electroplating
- 那一種曝光技術光罩較易污染 (A) Contact, (B) Proximity, (C) Projection, (D) 以上皆同
- 曝光時何種光源可定義較細之線寬, (A) g-line (436nm), (B) i-line (365nm), (C) KrF (248nm), (D) ArF (193nm)
- 一般而言, 何者有較佳之蝕刻速率 (etching rate): (A) ion etching, (B) sputter etching, (C) wet etching, (D) 以上皆同
- 一般而言, 何者有較佳之選擇比 (selectivity): (A) ion etching, (B) sputter etching, (C) wet etching, (D) 以上皆同
- Si wet anisotropic etching 無法製造 (A) cavity, (B) plate, (C) mesa, (D) circular channel
- 對於 KOH 蝕刻液而言, 蝕刻速率最慢的矽晶格面是 (A) (100), (B) (110), (C) (212), (D) (111)
- 有些 bulk micromachining 的懸浮結構如 clamped-clamped beam 和傳統機械結構不同, 主要是受限於何種製程 (A) deposition, (B) photolithography, (C) etching, (D) bonding
- 一般而言, 經由 PVD 的 thin film materials 的成份為多晶和非晶, 因此其蝕刻的方式為 (A) isotropic etching, (B) anisotropic etching, (C) 以上皆有可能, (D) 以上皆非
- 何者具有較高的 bonding temperature (A) Anodic bonding, (B) Fusion bonding, (C) Eutectic bonding, (D) Epoxy bonding
- Anodic bonding 常選用 Pyrex 7740 玻璃, 主因是那項材料特性? (A) stiffness, (B) thermal expansion coefficient, (C) density, (D) dielectric constant
- 何者在進行接合時, 接合面需介質輔助 (A) Si-Glass anodic bonding, (B) Si-Si fusion bonding, (C) Si-Si eutectic bonding, (D) 以上皆有可能
- LIGA 製程不包括 (A) Lithography, (B) Bonding, (C) Electroplating, (D) Molding
- 同步輻射光所提供的是何種製程 (A) Laser LIGA, (B) X-ray LIGA, (C) SOI MEMS, (D) CMOS.
- 何種元件沒有磨耗的問題 (A) Comb drive, (B) Micro motor, (C) Spindle, (D) Hinge

二、简答题 (30%)

1. **Deposition:** (1) What's **step coverage**? (2) Why **sputter** could give a better step coverage, as compare with **evaporation**? (3) Why **LPCVD** could give a better step coverage, as compare with **APCVD**. (6%)

2. **Photolithography:** What is **alignment mark**? Show two approaches for double-side alignment (6%)

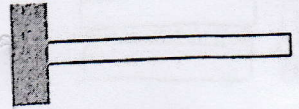
3. **Etching:** we could use the "time-control" etching to define the thickness of MEMS structures (e.g. the plate thickness of pressure sensor), (1) what's the problem the "time-control" etching may cause for mass production? (2) how to solve this problem, and give an example (6%)

4. **Etching:** (1) Show the etching mechanism of RIE, (2) why anisotropic etching can be achieved using RIE

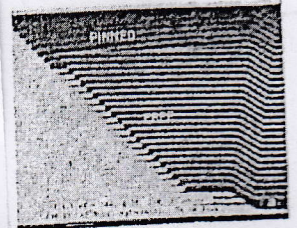
for anodic bonding? (2) Show a design to combine the advantages of the above two electrodes. (6%)

三、問答題 (50%+10%)

1. MEMS design: The bending stiffness of surface micromachined cantilever could be different with that of the design value. Show the fabrication process of surface micromachined poly-Si cantilever, and indicate five possible reasons (give a short explanation) to cause the difference of bending stiffness (as compare with that predicted from the ideal cantilever beam model). (10%)



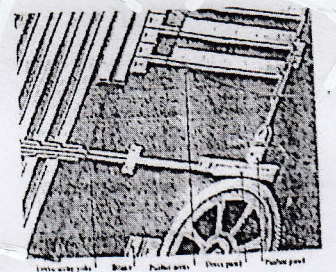
Ideal cantilever



Fabricated cantilever
(Mastrangelo, 1993)

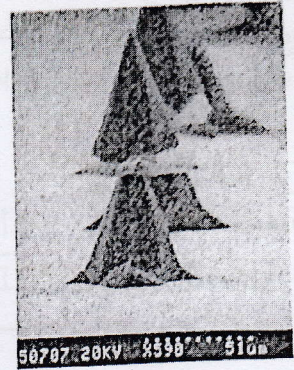
2. MEMS design: Show the processes to fabricate (a) 1 μ m thick bulk micromachining cantilever, (b) 5 μ m thick bulk micromachining cantilever, (c) 10 μ m thick cantilever on SOI wafer, (d) 30 μ m thick cantilever on (111) substrate, (e) 100 μ m thick LIGA micromachined cantilever beam. (10%)

3. MEMS design: (1) Indicating the thermal actuators on photo and also showing its operation principle, and (2) explaining the operation mechanism of the device to enable the angular motion of rotor (10%)



Comtois and Bright 1997

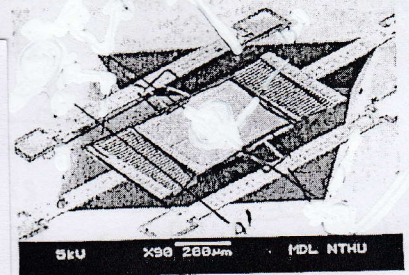
4. **Bulk Micromachining:** Show the fabrication processes to fabricate the micro Velcro below. Note that this one has a sharp tip to enable the easy intrusion. (10%)



R. Dizon, et. al., 1992

5. **Hybrid Micromachining:** Figure shows the 1-axis scanning mirror fabricated using the hybrid micromachining processes. (10%)

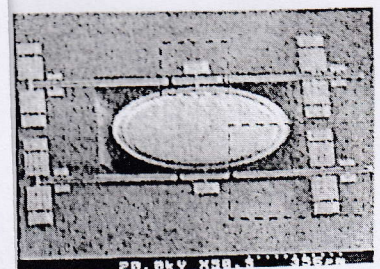
- (1) Indicate key components (vertical comb, spring, and rigid support/mirror) and their cross sections
- (2) Show the fabrication processes for these components
- (3) Illustrate the main mask to define the feature of scanner



MDL, NTHU

6. **Microsystem:** Figure shows the V-axis scanning mirror fabricated using the hybrid micromachining processes. The actuator and coupler are marked with dash lines in figure. (10%)

- (1) Show the merits of the actuator in terms of the driving voltage and output displacement
- (2) What's the purpose of the coupler
- (3) How to enable the mirror to scan at a large angle and high frequency



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